Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\left[\sqrt{f(GHZ)}\right] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

| Modulation | Channel Freq. (GHz) | Conduct ed power (dBm) | Conducte | Tune-up power (dBm) | Max tune-up power (dBm) | Max tune-up power (mW) | Distance (mm) | Result calculation | SAR Exclusion threshold | SAR test exclusion |
|------------|---------------------------|------------------------------|----------|---------------------------|----------------------------------|---------------------------------|------------------|-----------------------|-------------------------------|-----------------------|
| BLE1M | 2.402 | 0.47 | 1.11 | 1±1 | 2 | 1.58 | <5 | 0.49127 | 3.00 | YES |
| | 2.440 | 0.55 | 1.14 | 1±1 | 2 | 1.58 | <5 | 0.49514 | 3.00 | YES |
| | 2.480 | 0.22 | 1.05 | 1±1 | 2 | 1.58 | <5 | 0.49918 | 3.00 | YES |
| BLE2M | 2.402 | 0.35 | 1.08 | 1±1 | 2 | 1.58 | <5 | 0.49127 | 3.00 | YES |
| | 2.440 | 0.5 | 1.12 | 1±1 | 2 | 1.58 | <5 | 0.49514 | 3.00 | YES |
| | 2.480 | 0.2 | 1.05 | 1±1 | 2 | 1.58 | <5 | 0.49918 | 3.00 | YES |

Conclusion:

For the max result : $0.49918 \le 3.0$ for 1g SAR, SAR is not required.

Alex

Signature:

Date: 2024-08-27

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